Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/670,587	BIAN, JINRU	
Examiner	Art Unit	
Gregory F Webb	1751	

	SEARCHED		
Class	Subclass	Date	Examiner
			•
			-

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
510	175,176	2/12/2007	GEW
134	1.3		
438	692		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
update	,	2/12/2007	